SCLS130B - DECEMBER 1982 - REVISED MAY 1997

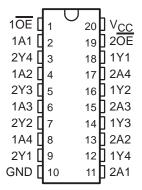
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- High-Current Outputs Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

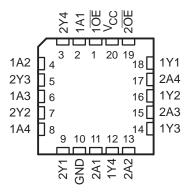
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC244 are organized as two 4-bit buffers/drivers with separate output-enable (OE) inputs. When OE is low, the device passes noninverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

The SN54HC244 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC244 is characterized for operation from –40°C to 85°C.

SN54HC244 . . . J OR W PACKAGE SN74HC244 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54HC244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer/driver)

INP	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z



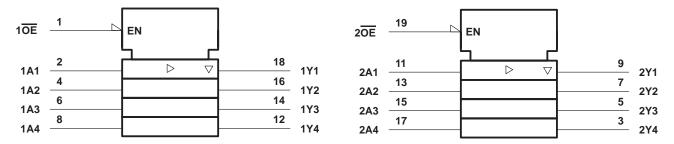
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SN54HC244, SN74HC244 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

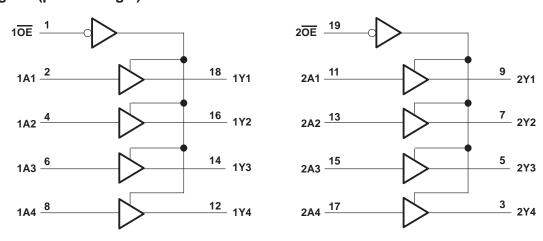
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see	e Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})) (see Note 1)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$		±35 mA
Continuous current through V _{CC} or GND		±70 mA
Package thermal impedance, θ_{JA} (see Note 2):	DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{sta}	–	65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SI	SN54HC244		SN	174HC24	4	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
ViH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 6 V	4.2			4.2			
	Low-level input voltage	V _{CC} = 2 V	0		0.5	0		0.5	V
VIL		V _{CC} = 4.5 V	0		1.35	0		1.35	
		V _{CC} = 6 V	0		1.8	0		1.8	
٧ı	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	ns
t _t	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	
		V _{CC} = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		, , , , , , , , , , , , , , , , , , ,	Т	A = 25°C	;	SN54HC244		SN74HC244		LINUT
PARAMETER			VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
			$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	6 V		±0.01	±0.5		±10		±5	μΑ
l _{CC}	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
C _i			2 V to 6 V		3	10		10		10	pF

SN54HC244, SN74HC244 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	λ = 25°C	;	SN54H	C244	SN74HC244		UNIT			
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT			
			2 V		40	115		170		145				
^t pd	Α	Y	4.5 V		13	23		34		29	ns			
			6 V		11	20		29		25				
			2 V		75	150		225		190				
^t en	ŌĒ	Y	4.5 V		15	30		45		38	ns			
					6 V		13	26		38		32		
	ŌĒ		2 V		75	150		225		190				
^t dis		ŌĒ Y	Υ	4.5 V		15	30		45		38	ns		
			6 V		13	26		38		32				
	Y		2 V		28	60		90		75				
t _t			Y	Υ	Υ	4.5 V		8	12		18		15	ns
			6 V		6	10		15		13				

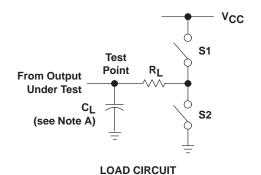
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T _A = 25°C			SN54HC244		SN74HC244		UNIT												
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT												
			2 V		56	165		245		210													
^t pd	А	Y	4.5 V		18	33		49		42	ns												
																	6 V		15	28		42	
	ŌĒ	Y	2 V		100	200		300		250													
t _{en}			4.5 V		20	40		60		50	ns												
				6 V		17	34		51		43												
			Y	Y	2 V		45	210		315		265											
t _t		Υ			4.5 V		17	42		63		53	ns										
			6 V		13	36		53		45													

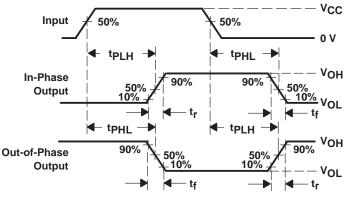
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

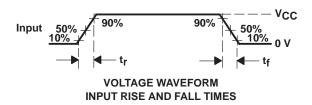
PARAMETER MEASUREMENT INFORMATION

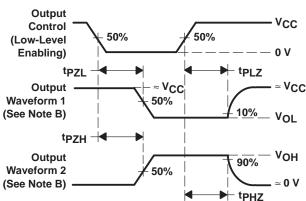


PARAI	PARAMETER		RL CL		S2	
	tPZH	1 kΩ	50 pF or	Open	Closed	
ten	tPZL	I	150 pF	Closed	Open	
f.u	t _{PHZ} 1 kΩ 50 pF		50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pi	Closed	Open	
t _{pd} or t _t			50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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